

Notice of References Cited	Application/Control No. 10/684,981	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0190435	09-2004	Hosoda et al.	369/283
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	P	05-234631 * 05-342631	12-1993	Japan	Isomura et al.	***
	Q	05-159358	06-1993	Japan	Akiyama et al.	***
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
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